IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Louis N. Koppel et al.

Application No.: NEW

Filed: HEREWITH

For: CALIBRATION AND ALIGNMENT OF X-RAY REFLECTOMETRIC

SYSTEMS.

Group Art Unit: 0

Examiner: Unknown

PRELIMINARY AMENDMENT

121 Spear Street, Suite 290 San Francisco, CA 94105 (415) 512-1312

M/S PATENT APPLICATION Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Prior to examining the above-identified divisional application, please amend the application as follows:

Amendments to the Specification begin on page 2 of this paper.

Amendment to the Claims are reflected in the listing of claims which begins on page 3 of this paper.

Remarks begin on page 6 of this paper.

Atty Docket No.: TWI-11720